

MARK FIELD, METHOD AND DEVICE FOR DETERMINING
POSITIONS

Abstract

The invention relates to a mark field (4), having

- at least two location marks (2) with information for the location of the respective location mark (2) in the mark field (4), and
- at least one position mark (3), which is or can be assigned to one of the location marks (2).

Furthermore, the present invention relates to a device for determining X-Y positions of structural features (11c) of structures (11) arranged on a substrate (7), wherein the X-Y positions relative to the mark field (4), which is fixed with respect to the substrate, can be determined.

Furthermore, the present invention relates to a corresponding method.

Figure 8.